



# STF17N62K3 STP17N62K3, STW17N62K3

N-channel 620 V, 0.28  $\Omega$  15.5 A, TO-220FP, TO-220, TO-247  
SuperMESH3™ Power MOSFET

## Features

Order codes	$V_{DSS}$	$R_{DS(on)}$ max.	$I_D$	$P_w$
STF17N62K3	620 V	< 0.34 $\Omega$	15.5 A	40 W
STP17N62K3	620 V	< 0.34 $\Omega$	15.5 A	190 W
STW17N62K3	620 V	< 0.34 $\Omega$	15.5 A	190 W

- 100% avalanche tested
- Extremely high dv/dt capability
- Gate charge minimized
- Very low intrinsic capacitance
- Improved diode reverse recovery characteristics
- Zener-protected

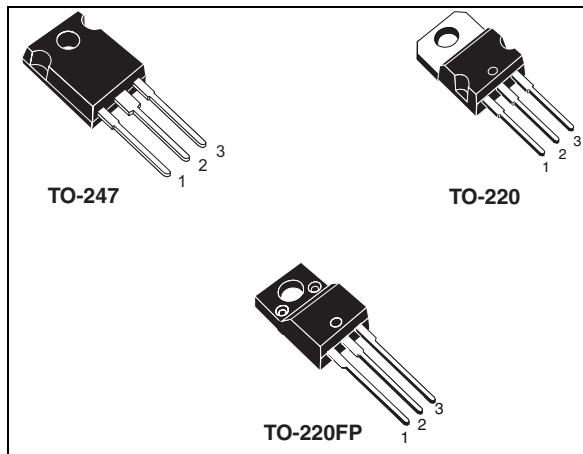
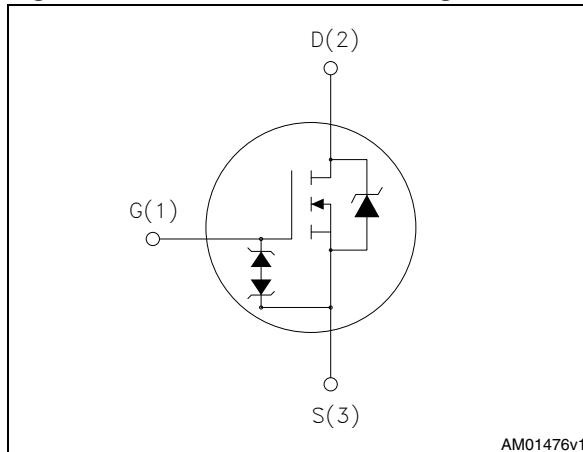


Figure 1. Internal schematic diagram



## Applications

- Switching applications

## Description

This SuperMESH3™ Power MOSFET is the result of improvements applied to STMicroelectronics' SuperMESH™ technology, combined with a new optimized vertical structure. This device boasts an extremely low on-resistance, superior dynamic performance and high avalanche capability, rendering it suitable for the most demanding applications.

Table 1. Device summary

Order codes	Marking	Package	Packaging
STF17N62K3	17N62K3	TO-220FP	Tube
STP17N62K3	17N62K3	TO-220	Tube
STW17N62K3	17N62K3	TO-247	Tube

## Contents

<b>1</b>	<b>Electrical ratings</b>	<b>3</b>
<b>2</b>	<b>Electrical characteristics</b>	<b>4</b>
2.1	Electrical characteristics (curves)	6
<b>3</b>	<b>Test circuits</b>	<b>9</b>
<b>4</b>	<b>Package mechanical data</b>	<b>10</b>
<b>5</b>	<b>Revision history</b>	<b>16</b>

# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

Symbol	Parameter	Value		Unit
		TO-220 TO-247	TO-220FP	
$V_{DS}$	Drain-source voltage ( $V_{GS} = 0$ )	620		V
$V_{GS}$	Gate- source voltage	$\pm 30$		V
$I_D$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	15.5	15.5 <sup>(1)</sup>	A
$I_D$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	10	10 <sup>(1)</sup>	A
$I_{DM}$ <sup>(2)</sup>	Drain current (pulsed)	62	62 <sup>(1)</sup>	A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ\text{C}$	190	40	W
$I_{AR}$ <sup>(3)</sup>	Avalanche current, repetitive or not-repetitive	15.5		A
$E_{AS}$ <sup>(4)</sup>	Single pulse avalanche energy	260		mJ
	Derating factor	1.52	0.32	W/ $^\circ\text{C}$
$dv/dt$ <sup>(5)</sup>	Peak diode recovery voltage slope	9		V/ns
$V_{ISO}$	Insulation withstand voltage (RMS) from all three leads to external heat sink ( $t = 1 \text{ s}; T_C = 25^\circ\text{C}$ )	2500		V
$T_{stg}$	Storage temperature	-55 to 150		$^\circ\text{C}$
$T_j$	Max. operating junction temperature	150		$^\circ\text{C}$

1. Limited only by temperature allowed.
2. Pulse width limited by safe operating area.
3. Pulse width limited by  $T_j$  max.
4. Starting  $T_j = 25^\circ\text{C}$ ,  $I_D = I_{AR}$ ,  $V_{DD} = 50\text{V}$ .
5.  $I_{SD} \leq 15.5 \text{ A}$ ,  $di/dt \leq 400 \text{ A}/\mu\text{s}$ ,  $V_{DD} = 80\% V_{(BR)DSS}$ ,  $V_{DS}$  peak <  $V_{(BR)DSS}$ .

**Table 3. Thermal data**

Symbol	Parameter	TO-220FP	TO-220	TO-247	Unit
$R_{thj-case}$	Thermal resistance junction-case max	3.13	0.66		$^\circ\text{C}/\text{W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max	62.5		50	$^\circ\text{C}/\text{W}$
$T_I$	Maximum lead temperature for soldering purpose	300		$^\circ\text{C}$	

## 2 Electrical characteristics

( $T_C = 25^\circ\text{C}$  unless otherwise specified)

**Table 4. On /off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage ( $V_{GS} = 0$ )	$I_D = 1 \text{ mA}$	620			V
$I_{\text{DSS}}$	Zero gate voltage drain current ( $V_{GS} = 0$ )	$V_{DS} = 620 \text{ V}$ $V_{DS} = 620 \text{ V}, T_C = 125^\circ\text{C}$			1 50	$\mu\text{A}$ $\mu\text{A}$
$I_{GSS}$	Gate-body leakage current ( $V_{DS} = 0$ )	$V_{GS} = \pm 20 \text{ V}$			$\pm 10$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 100 \mu\text{A}$	3	3.75	4.5	V
$R_{DS(\text{on})}$	Static drain-source on resistance	$V_{GS} = 10 \text{ V}, I_D = 7.5 \text{ A}$		0.28	0.34	$\Omega$

**Table 5. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$ $C_{oss}$ $C_{rss}$	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 50 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0$	-	3100 200 35	-	pF pF pF
$C_{o(\text{tr})}^{(1)}$	Equivalent capacitance time related	$V_{DS} = 0 \text{ to } 496 \text{ V}, V_{GS} = 0$	-	140	-	pF
$C_{o(\text{er})}^{(2)}$	Equivalent capacitance energy related		-	200	-	pF
$R_G$	Intrinsic gate resistance	$f = 1 \text{ MHz}$ open drain	-	2.3	-	$\Omega$
$Q_g$ $Q_{gs}$ $Q_{gd}$	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 496 \text{ V}, I_D = 15.5 \text{ A},$ $V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 20</a> )	-	105 16 62	-	nC nC nC

1.  $C_{oss\text{ eq}}$  time related is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$
2.  $C_{oss\text{ eq}}$  energy related is defined as a constant equivalent capacitance giving the same stored energy as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

**Table 6. Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 310 \text{ V}$ , $I_D = 7.5 \text{ A}$ , $R_G = 4.7 \Omega$ , $V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 19</a> )	-	22	-	ns
$t_r$	Rise time			29		
$t_{d(off)}$	Turn-off-delay time			110	-	ns
$t_f$	Fall time			62		

**Table 7. Source drain diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$ $I_{SDM}^{(1)}$	Source-drain current		-	15.5 62	A A	A
	Source-drain current (pulsed)					
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 15.5 \text{ A}$ , $V_{GS} = 0$	-		1.6	V
$t_{rr}$ $Q_{rr}$ $I_{RRM}$	Reverse recovery time	$I_{SD} = 15.5 \text{ A}$ , $di/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 60 \text{ V}$ (see <a href="#">Figure 24</a> )	-	380	ns nC A	ns nC A
	Reverse recovery charge			5000		
	Reverse recovery current			26		
$t_{rr}$ $Q_{rr}$ $I_{RRM}$	Reverse recovery time	$I_{SD} = 15.5 \text{ A}$ , $di/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 60 \text{ V}$ , $T_j = 150^\circ\text{C}$ (see <a href="#">Figure 24</a> )	-	450	ns nC A	ns nC A
	Reverse recovery charge			6500		
	Reverse recovery current			29		

1. Pulse width limited by safe operating area
2. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

**Table 8. Gate-source Zener diode**

Symbol	Parameter	Test conditions	Min	Typ	Max	Unit
$BV_{GSO}$	Gate-source breakdown voltage	$I_{GS} = \pm 1 \text{ mA}$ (open drain)	30			V

The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

## 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area for TO-220FP

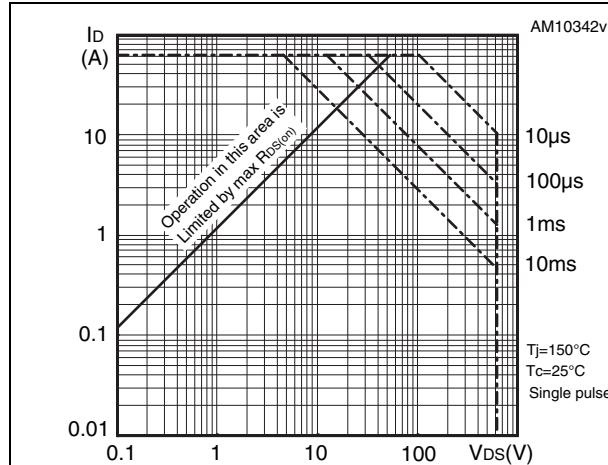


Figure 3. Thermal impedance for TO-220FP

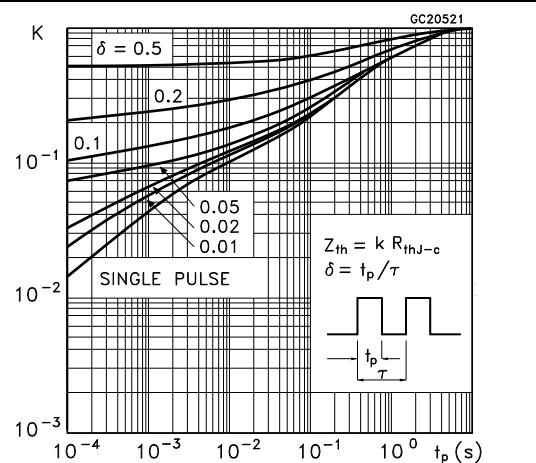


Figure 4. Safe operating area for TO-220

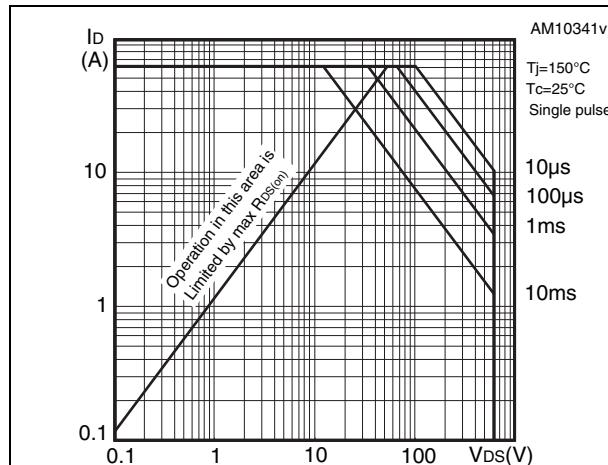


Figure 5. Thermal impedance for TO-220

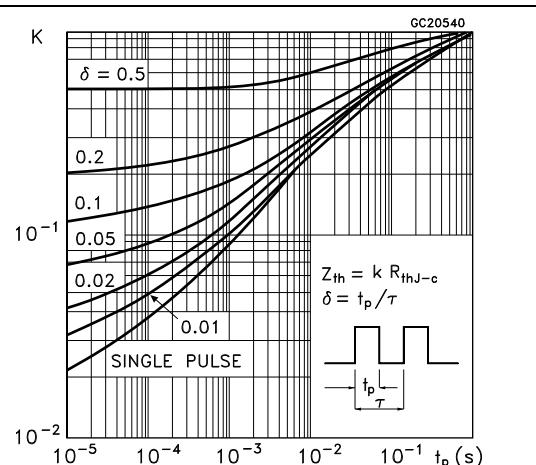


Figure 6. Safe operating area for TO-247

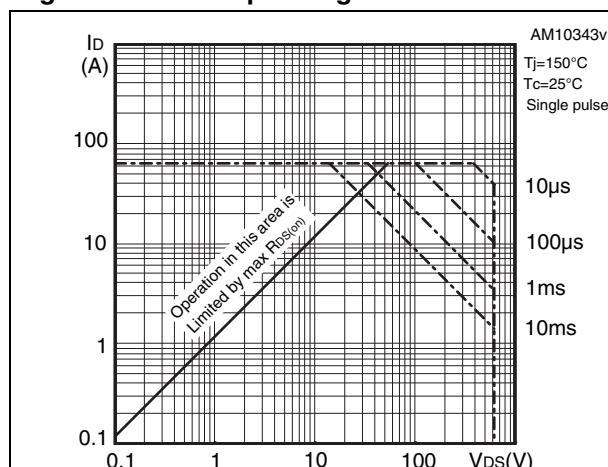
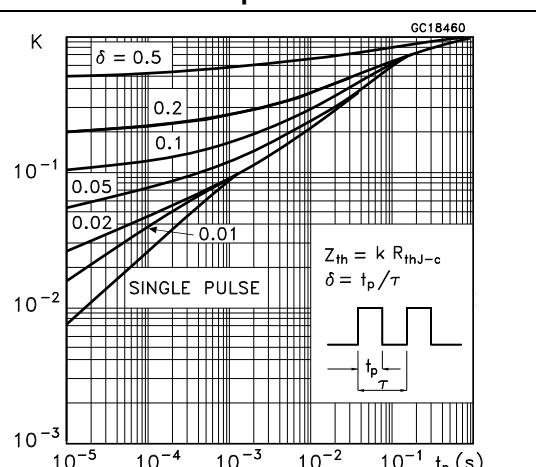
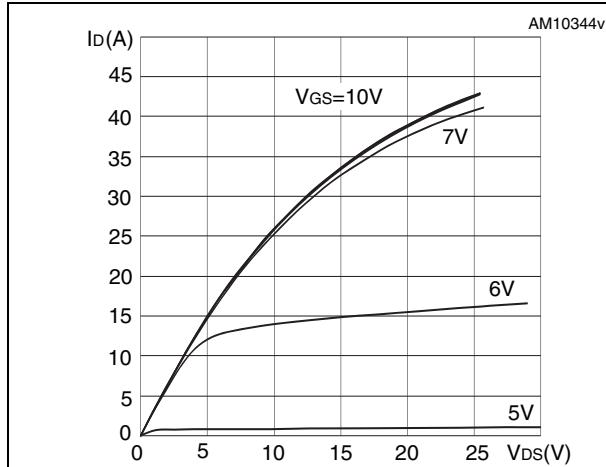
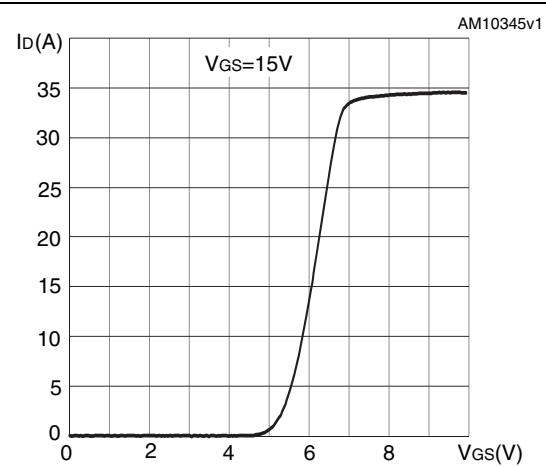
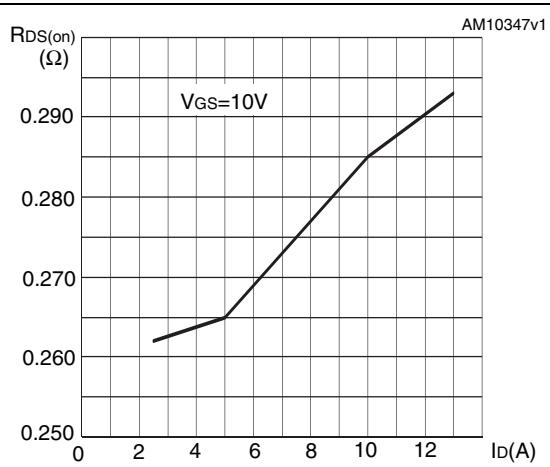
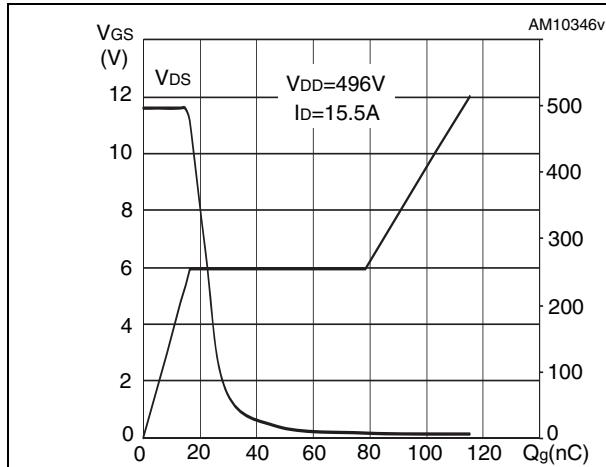
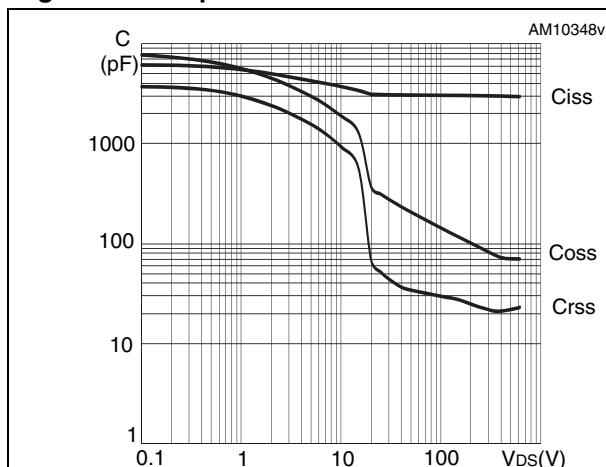
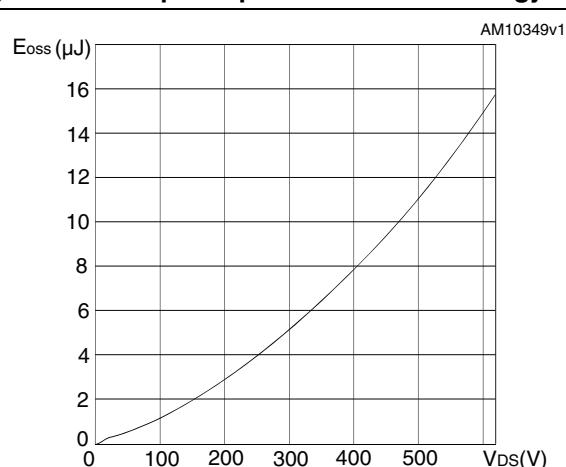
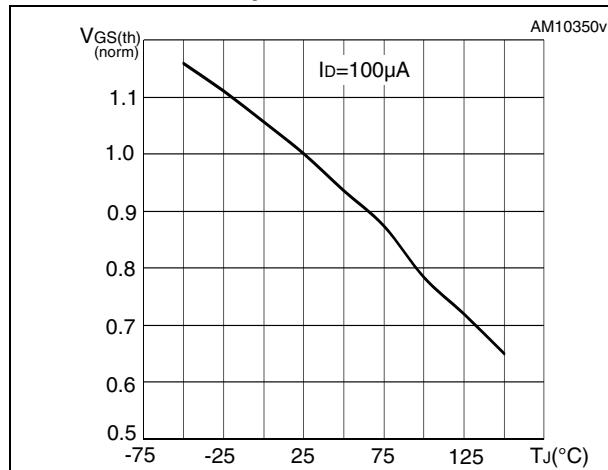


Figure 7. Thermal impedance for TO-247

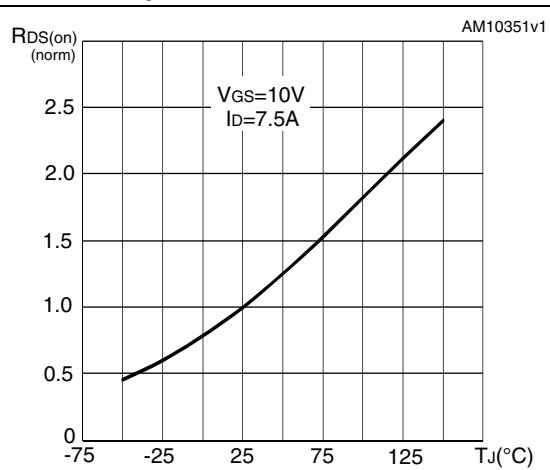


**Figure 8. Output characteristics****Figure 9. Transfer characteristics****Figure 10. Gate charge vs gate-source voltage**    **Figure 11. Static drain-source on resistance****Figure 12. Capacitance variations****Figure 13. Output capacitance stored energy**

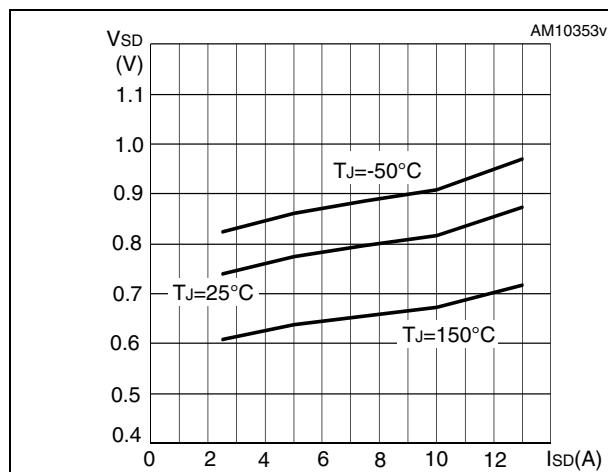
**Figure 14. Normalized gate threshold voltage vs temperature**



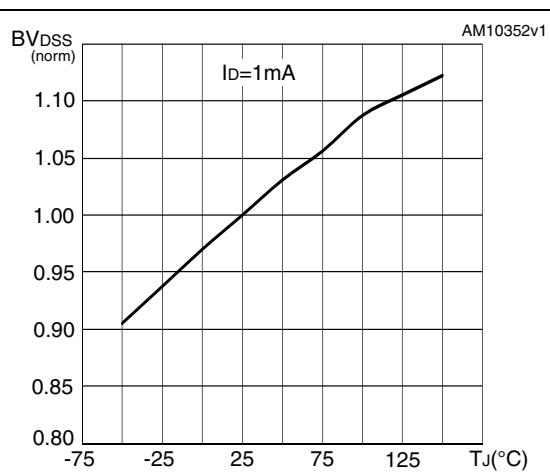
**Figure 15. Normalized on resistance vs temperature**



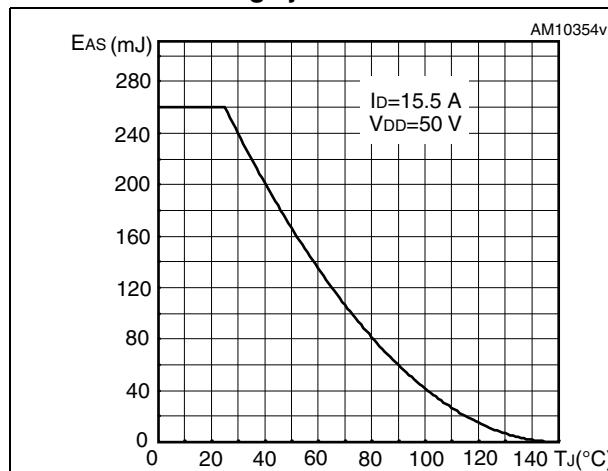
**Figure 16. Source-drain diode forward characteristics**



**Figure 17. Normalized B<sub>VDSS</sub> vs temperature**

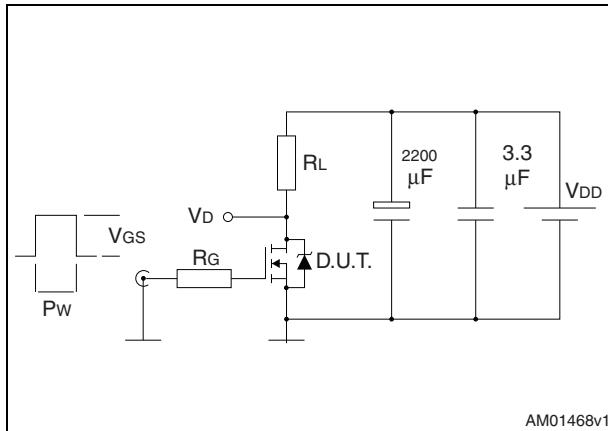


**Figure 18. Maximum avalanche energy vs starting T<sub>j</sub>**

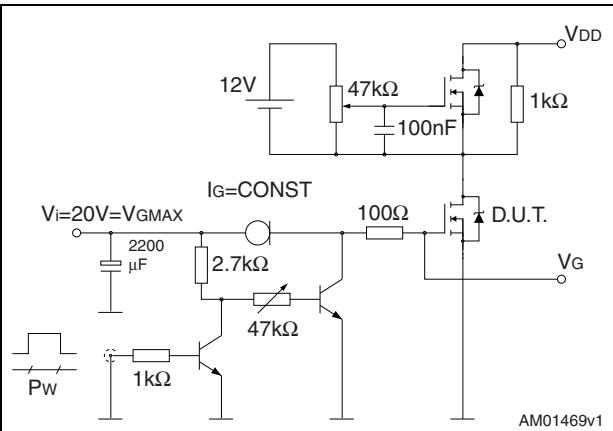


### 3 Test circuits

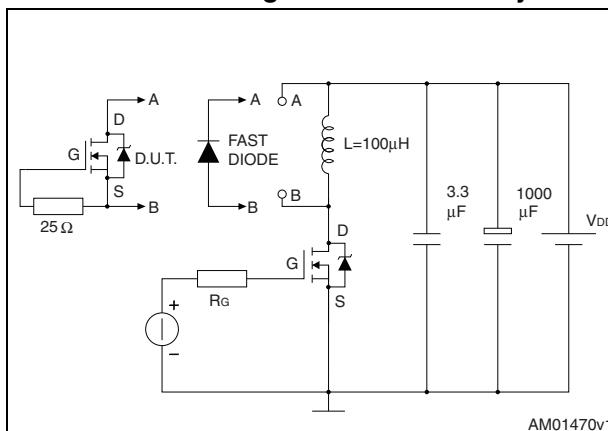
**Figure 19. Switching times test circuit for resistive load**



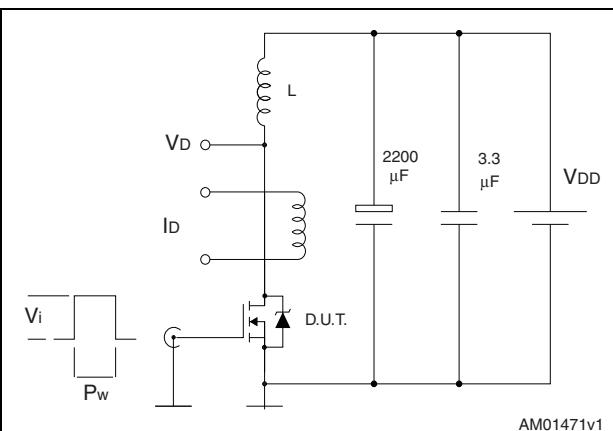
**Figure 20. Gate charge test circuit**



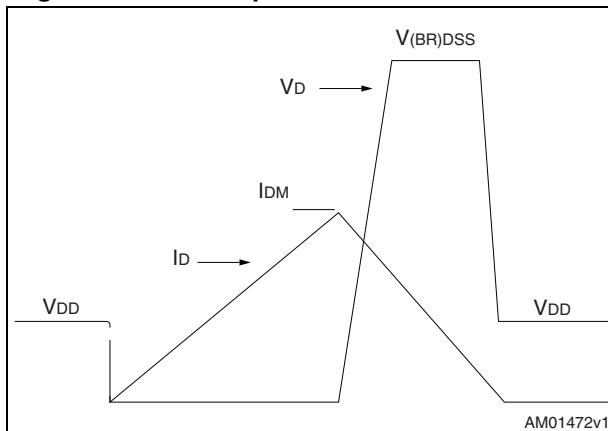
**Figure 21. Test circuit for inductive load switching and diode recovery times**



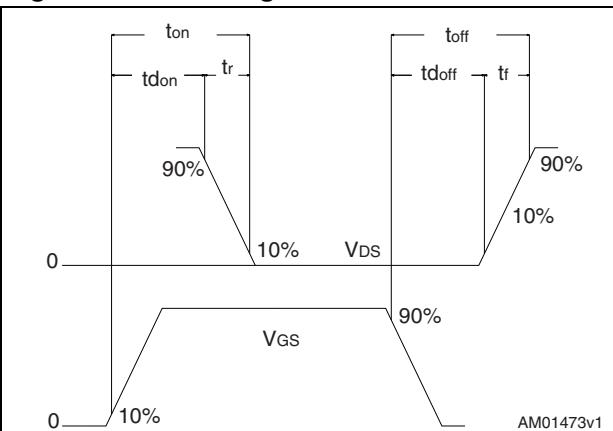
**Figure 22. Unclamped Inductive load test circuit**



**Figure 23. Unclamped inductive waveform**



**Figure 24. Switching time waveform**

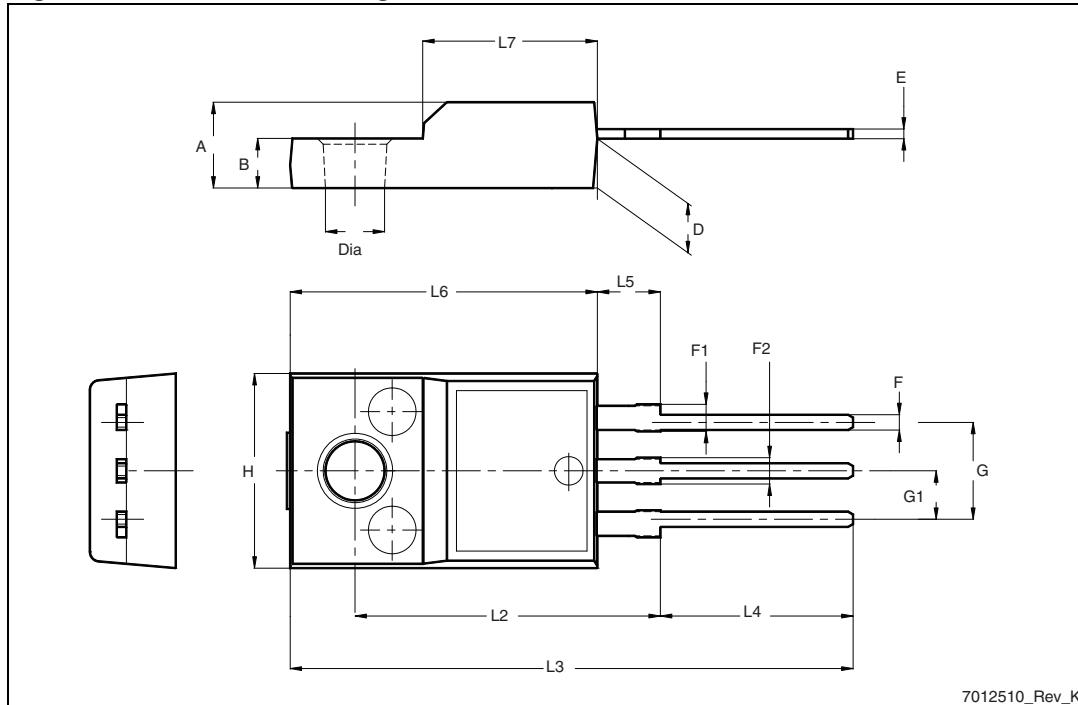


## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK is an ST trademark.

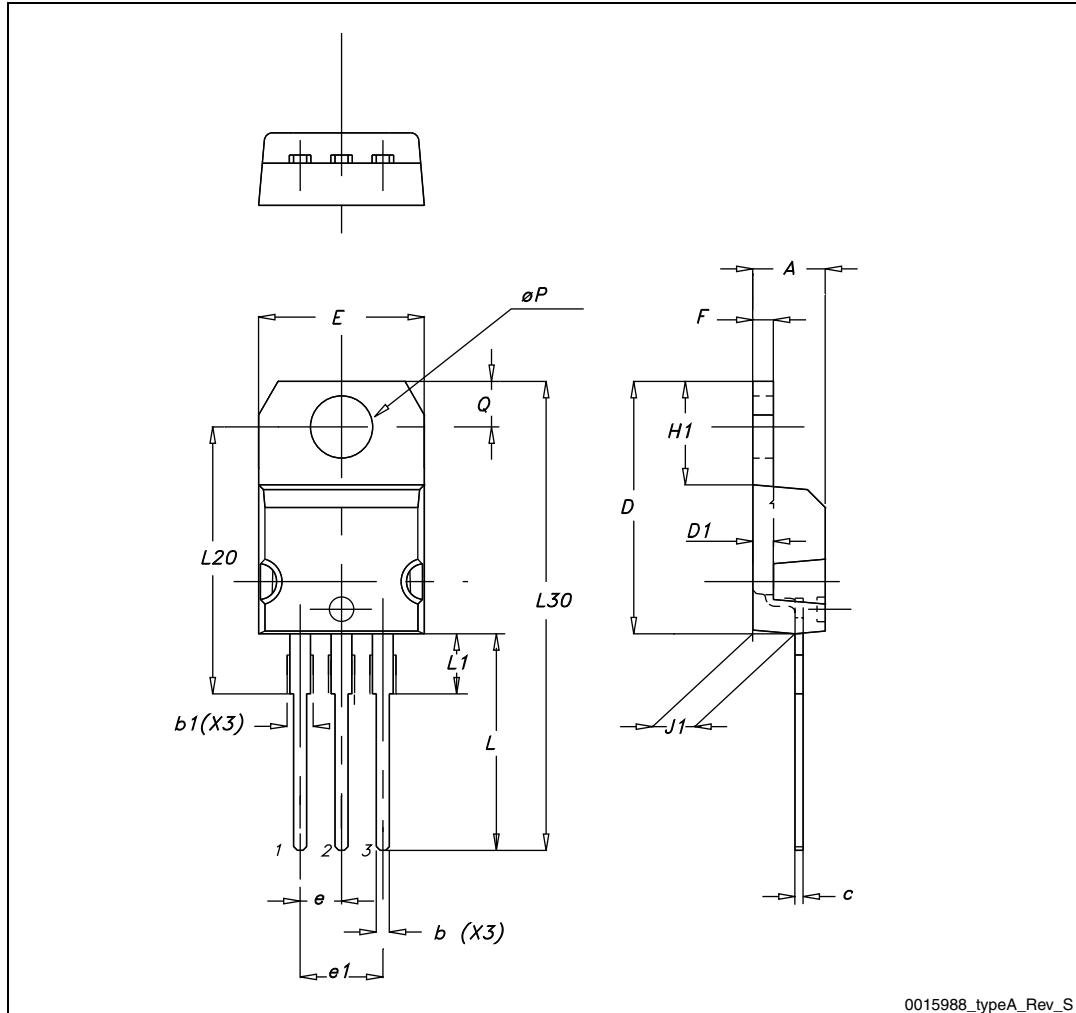
**Table 9.** TO-220FP mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.4		4.6
B	2.5		2.7
D	2.5		2.75
E	0.45		0.7
F	0.75		1
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.2
G1	2.4		2.7
H	10		10.4
L2		16	
L3	28.6		30.6
L4	9.8		10.6
L5	2.9		3.6
L6	15.9		16.4
L7	9		9.3
Dia	3		3.2

**Figure 25.** TO-220FP drawing

**Table 10.** TO-220 type A mechanical data

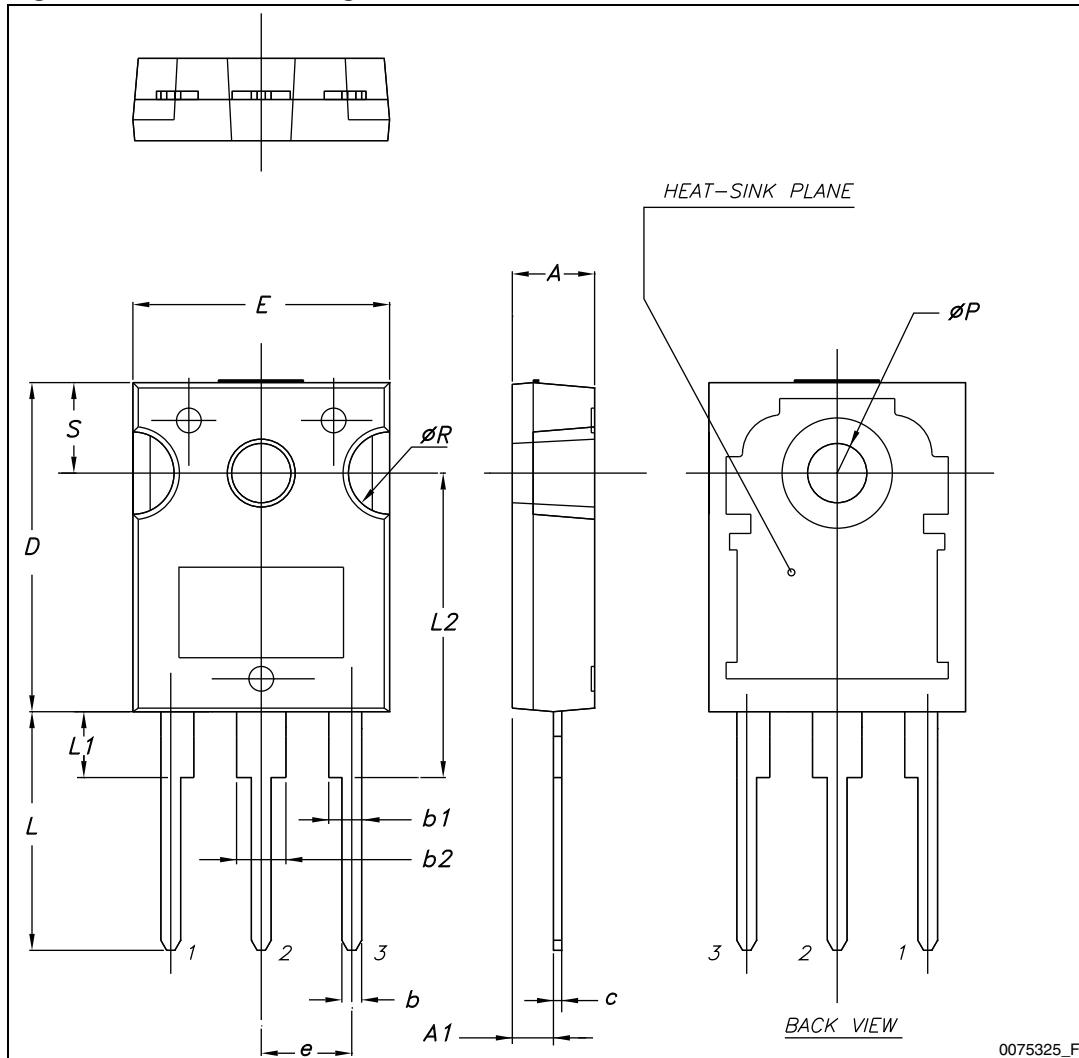
Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
b	0.61		0.88
b1	1.14		1.70
c	0.48		0.70
D	15.25		15.75
D1		1.27	
E	10		10.40
e	2.40		2.70
e1	4.95		5.15
F	1.23		1.32
H1	6.20		6.60
J1	2.40		2.72
L	13		14
L1	3.50		3.93
L20		16.40	
L30		28.90	
ØP	3.75		3.85
Q	2.65		2.95

**Figure 26.** TO-220 type A drawing

**Table 11.** TO-247 mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
c	0.40		0.80
D	19.85		20.15
E	15.45		15.75
e		5.45	
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
ØP	3.55		3.65
ØR	4.50		5.50
S		5.50	

Figure 27. TO-247 drawing



0075325\_F

## 5 Revision history

**Table 12. Document revision history**

Date	Revision	Changes
11-Nov-2008	1	First release.
27-Jul-2011	2	<i>Section 2.1: Electrical characteristics (curves)</i> has been updated. Minor text changes.

**Please Read Carefully:**

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

**UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.**

**UNLESS EXPRESSLY APPROVED IN WRITING BY TWO AUTHORIZED ST REPRESENTATIVES, ST PRODUCTS ARE NOT RECOMMENDED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE. ST PRODUCTS WHICH ARE NOT SPECIFIED AS "AUTOMOTIVE GRADE" MAY ONLY BE USED IN AUTOMOTIVE APPLICATIONS AT USER'S OWN RISK.**

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

© 2011 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Philippines - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

[www.st.com](http://www.st.com)

